

<b>Notice of References Cited</b>	Application/Control No. 10/585,691	Applicant(s)/Patent Under Reexamination FUKUSHIMA ET AL.	
	Examiner HEE-YONG KIM	Art Unit 2621	Page 1 of 1

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*	B	US-6,064,424 A	05-2000	van Berkel et al.	348/51
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**NON-PATENT DOCUMENTS**

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